

Technical documentation





SN74LV164A-Q1 SCLS886 - DECEMBER 2022

# SN74LV164A-Q1 Automotive 8-Bit Parallel-Out Serial Shift Registers

# 1 Features

Texas

INSTRUMENTS

- AEC-Q100 qualified for automotive applications:
  - \_ Device temperature grade 1: -40°C to +125°C, Τ<sub>A</sub>
  - **Device HBM ESD Classification Level 2**
  - Device CDM ESD Classification Level C6
- 2-V to 5.5-V V<sub>CC</sub> operation
- Maximum t<sub>pd</sub> of 10.5 ns at 5 V
- Typical V<sub>OLP</sub> (output ground bounce) • < 0.8 V at  $V_{CC}$  = 3.3 V,  $T_A$  = 25°C
- Typical V<sub>OHV</sub> (output V<sub>OH</sub> undershoot) > 2.3 V at V<sub>CC</sub> = 3.3 V, T<sub>A</sub> =  $25^{\circ}$ C
- loff supports live insertion, partial power-down mode, and back-drive protection
- Support mixed-mode voltage operation on all ports
- Latch-up performance exceeds 250 mA per JESD 17

## 2 Applications

- **Output expansion**
- LED matrix control
- 7-segment display control

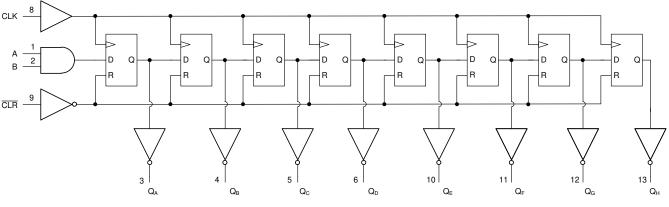
# **3 Description**

The SN74LV164A-Q1 devices are 8-bit parallel-out serial shift registers designed for 2-V to 5.5-V  $V_{CC}$ operation.

Device	Information <sup>(</sup>	1)
	momunon	

PART NUMBER	PACKAGE	BODY SIZE (NOM)
SN74LV164A-Q1	BQA (WQFN, 14)	3.00 mm × 2.50 mm

(1)For all available packages, see the orderable addendum at the end of the data sheet.



Logic Diagram (Positive Logic)





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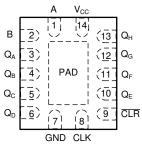
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# **4 Revision History**

DATE	REVISION	NOTES
December 2022	*	Initial Release



## **5** Pin Configuration and Functions



#### Figure 5-1. BQA Package, 14-PIN WQFN (Top View)

#### Table 5-1. Pin Functions

PIN		TYPE <sup>(1)</sup>	DESCRIPTION		
NAME	NO.		DESCRIPTION		
A	1	I	Serial input A		
В	2	I	Serial input B		
Q <sub>A</sub>	3	0	Output A		
Q <sub>B</sub>	4	0	Output B		
Q <sub>C</sub>	5	0	Output C		
Q <sub>D</sub>	6	0	Output D		
GND	7	G	Ground pin		
CLK	8	I	Storage clock		
CLR	9	I	Storage clear		
Q <sub>E</sub>	10	0	Output E		
Q <sub>F</sub>	11	0	Output F		
Q <sub>G</sub>	12	0	Output G		
Q <sub>H</sub>	13	0	Output H		
Q <sub>H'</sub>	11	0	Q <sub>H</sub> inverted		
V <sub>CC</sub>	14	Р	Power pin		
Thermal pad		_	Thermal pad <sup>(2)</sup>		

(1) I = Input, O = Output, I/O = Input or Output, G = Ground, P = Power.

(2) WBQA package only



## 6 Specifications 6.1 Absolute Maximum Ratings<sup>(1)</sup>

over operating free-air temperature range (unless otherwise noted)

			MIN	MAX	UNIT
V <sub>CC</sub>	Supply voltage		-0.5	7	V
VI	Input voltage <sup>(2)</sup>		-0.5	7	V
Vo	Voltage applied to any output in the high-impedance or p	power-off state <sup>(2)</sup>	-0.5	7	V
Vo	Output voltage <sup>(2) (3)</sup>		-0.5	V <sub>CC</sub> + 0.5	V
I <sub>IK</sub>	Input clamp current	V <sub>1</sub> < 0		-20	mA
I <sub>OK</sub>	Output clamp current	V <sub>O</sub> < 0		-50	mA
I <sub>O</sub>	Continuous output current	Continuous output current $V_0 = 0$ to $V_{CC}$		±25	mA
	Continuous current through V <sub>CC</sub> or GND			±50	mA
T <sub>stg</sub>	Storage temperature		-65	150	°C

(1) Operation outside the Absolute Maximum Ratings may cause permanent device damage. Absolute maximum ratings do not imply functional operation of the device at these or any other conditions beyond those listed under Recommended Operating Conditions. If briefly operating outside the Recommended Operating Conditions but within the Absolute Maximum Ratings, the device may not sustain damage, but it may not be fully functional. Operating the device in this manner may affect device reliability, functionality, performance, and shorten the device lifetime.

(2) The input and output negative-voltage ratings may be exceeded if the input and output current ratings are observed.

(3) This value is limited to 5.5 V maximum.

### 6.2 ESD Ratings

			VALUE	UNIT
	Electrostatic	Human body model (HBM), per AEC Q100-002 HBM ESD Classification Level $2^{(1)}$	±4000	
V <sub>(ESD)</sub>	discharge	Charged device model (CDM), per AEC Q100-011 CDM ESD Classification Level C4B	±2000	V

(1) AEC Q100-002 indicate that HBM stressing shall be in accordrance with the ANSI/ESDA/JEDEC JS-001 specification.



### 6.3 Recommended Operating Conditions

over recommended operating free-air temperature range (unless otherwise noted)<sup>(1)</sup>

			MIN	MAX	UNIT	
V <sub>CC</sub>	Supply voltage		2	5.5	V	
		V <sub>CC</sub> = 2 V	1.5			
V		$V_{CC}$ = 2.3 V to 2.7 V	V <sub>CC</sub> × 0.7		V	
V <sub>IH</sub>	High-level input voltage	V <sub>CC</sub> = 3 V to 3.6 V	V <sub>CC</sub> × 0.7		v	
		$V_{CC}$ = 4.5 V to 5.5 V	V <sub>CC</sub> × 0.7			
		V <sub>CC</sub> = 2 V		0.5		
VIL	Low-level input voltage	$V_{CC}$ = 2.3 V to 2.7 V		V <sub>CC</sub> × 0.3	V	
	Low-level input voltage	V <sub>CC</sub> = 3 V to 3.6 V		$V_{CC} \times 0.3$	v	
		$V_{CC}$ = 4.5 V to 5.5 V		$V_{CC} \times 0.3$		
VI	Input voltage		0	5.5	V	
Vo	Output voltage		0	V <sub>CC</sub>	V	
		V <sub>CC</sub> = 2 V		-50	μA	
	High lovel output ourrent	$V_{CC}$ = 2.3 V to 2.7 V		-2		
I <sub>ОН</sub>	High-level output current	V <sub>CC</sub> = 3 V to 3.6 V		-6	mA	
		$V_{CC}$ = 4.5 V to 5.5 V		–12		
		V <sub>CC</sub> = 2 V		50	μA	
		$V_{CC}$ = 2.3 V to 2.7 V		2		
I <sub>OL</sub>	Low-level output current	V <sub>CC</sub> = 3 V to 3.6 V		6	mA	
		$V_{CC}$ = 4.5 V to 5.5 V		12		
		V <sub>CC</sub> = 2.3 V to 2.7 V		200		
Δt/Δv	Input transition rise or fall rate	V <sub>CC</sub> = 3 V to 3.6 V		100	ns/V	
		$V_{CC}$ = 4.5 V to 5.5 V		20		
T <sub>A</sub>	Operating free-air temperature	·	-40	125	°C	

(1) All unused inputs of the device must be held at V<sub>CC</sub> or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*.

### 6.4 Thermal Information

		SN74LV164A-Q1	
	THERMAL METRIC <sup>(1)</sup>	BQA (WQFN)	UNIT
		14 PINS	-
R <sub>θJA</sub>	Junction-to-ambient thermal resistance	88.3	
R <sub>0JC(top)</sub>	Junction-to-case (top) thermal resistance	90.9	
R <sub>θJB</sub>	Junction-to-board thermal resistance	56.8	°C/W
Ψ <sub>JT</sub>	Junction-to-top characterization parameter	9.9	C/W
Ψ <sub>JB</sub>	Junction-to-board characterization parameter	56.7	
R <sub>0JC(bot)</sub>	Junction-to-case (bottom) thermal resistance	33.4	

(1) For more information about traditional and new thermal metrics, see IC Package Thermal Metrics

## **6.5 Electrical Characteristics**

PARAMETER	TEST CONDITIONS	N N	-40°0	C to 125°C	UNIT	
PARAMETER	TEST CONDITIONS	V <sub>cc</sub>	MIN	TYP MAX	UNIT	
	I <sub>OH</sub> = -50 μA	2 V to 5.5 V	V <sub>CC</sub> – 0.1			
V <sub>OH</sub>	I <sub>OH</sub> = -2 mA	2.3 V	2		V	
	I <sub>OH</sub> = -6 mA	3 V	2.48			
	I <sub>OH</sub> = -12 mA	4.5 V	3.8			
	Ι <sub>ΟL</sub> = 50 μΑ	2 V to 5.5 V		0.1	V	
V <sub>OL</sub>	I <sub>OL</sub> = 2 mA	2.3 V		0.4		
	I <sub>OL</sub> = 6 mA	3 V		0.44		
	I <sub>OL</sub> = 12 mA	4.5 V		0.55		
lı.	V <sub>I</sub> = 5.5 V or GND	0 to 5.5 V		±1	μA	
I <sub>CC</sub>	$V_1 = V_{CC}$ or GND, $I_0 = 0$	5.5		20	μA	
I <sub>off</sub>	$V_{I}$ or $V_{O}$ = 0 to 5.5 V	0		5	μA	
Ci	V <sub>I</sub> = V <sub>CC</sub> or GND	3.3 V		2.2	pF	

over recommended operating free-air temperature range (unless otherwise noted)

## 6.6 Timing Requirements: $V_{CC}$ = 2.5 V ± 0.2 V

over recommended operating free-air temperature range (unless otherwise noted) (see Figure 7-1)

-		T <sub>A</sub> = 25°	с	–40°C to 125°C	:	UNIT	
		MIN	MAX	MIN	MAX	UNIT	
t <sub>w</sub> Pulse duration	CLR low	6		6.5			
	Fuise duration	CLK high or low	6.5		7.5		ns
t <sub>su</sub> Setup time	Satur time	Data before CLK↑	6.5		8.5		ns
	CLR inactive	3		3		115	
t <sub>h</sub>	Hold time	Data after CLK↑	-0.5		0		ns

## 6.7 Timing Requirements: V<sub>CC</sub> = 3.3 V $\pm$ 0.3 V

over recommended operating free-air temperature range (unless otherwise noted) (see Figure 7-1)

			T <sub>A</sub> = 25°	2	-40°C to 12	5°C	UNIT
			MIN	MAX	MIN	°C MAX	UNIT
	Pulse duration	CLR low	5		5		ns
L <sub>W</sub>		CLK high or low	5		5		115
	Setup time	Data before CLK↑	5		6		
t <sub>su</sub>	Setup time	CLR inactive	2.5		2.5		ns
t <sub>h</sub>	Hold time	Data after CLK↑	0		0		ns



## 6.8 Timing Requirements: $V_{CC}$ = 5 V ± 0.5 V

over recommended operating free-air temperature range (unless otherwise noted) (see Figure 7-1)

	1 5	1 0 (		/ \	/		
			T <sub>A</sub> = 25°0	<b>C</b>	–40°C to 125°	c	UNIT
			MIN	MAX	MIN	MAX	UNIT
	Pulse duration	CLR low	5		5		20
<sup>w</sup>		CLK high or low	5		5		ns
	Setup time	Data before CLK↑	4.5		4.5		20
Lsu	Setup time	CLR inactive	2.5		2.5		ns
t <sub>h</sub>	Hold time	Data after CLK↑	1		1		ns

## 6.9 Switching Characteristics: $V_{CC}$ = 2.5 V ± 0.2 V

over recommended operating free-air temperature range (unless otherwise noted) (see Figure 7-1)

PARAMETER	FROM	то	LOAD	T,	<sub>A</sub> = 25°C		–40°C to 12	5°C	UNIT
FARAMETER	(INPUT)	(OUTPUT)	CAPACITANCE	MIN	TYP	MAX	MIN	MAX	UNIT
f			C <sub>L</sub> = 15 pF	55	105		50		MHz
Imax			C <sub>L</sub> = 50 pF	45	85		40		IVITIZ
t <sub>pd</sub>	CLK	Q	0 - 15 - 15		9.2	17.6	1	21	
t <sub>PHL</sub>	CLR	Q	C <sub>L</sub> = 15 pF		8.6	16	1	18.5	ns
t <sub>pd</sub>	CLK	Q	C = 50 pE		11.5	21.1	1	25	20
t <sub>PHL</sub>	CLR	Q	C <sub>L</sub> = 50 pF		10.8	19.5	1	22.5	ns

### 6.10 Switching Characteristics: $V_{CC}$ = 3.3 V ± 0.3 V

over recommended operating free-air temperature range (unless otherwise noted) (see Figure 7-1)

PARAMETER	FROM	то	LOAD	T <sub>A</sub> = 25°C			-40°C to 12	UNIT	
FARAMETER	(INPUT)	(OUTPUT)	CAPACITANCE	MIN	TYP	MAX	MIN	MAX	UNIT
f			C <sub>L</sub> = 15 pF	80	155		65		MHz
Imax			C <sub>L</sub> = 50 pF	50	120		45		IVITIZ
t <sub>pd</sub>	CLK	Q	0 - 15 - 15		6.4	12.8	1	16	
t <sub>PHL</sub>	CLR	Q	C <sub>L</sub> = 15 pF		6	12.8	1	16	ns
t <sub>pd</sub>	CLK	Q	C = 50 pE		8.3	16.3	1	19.5	<b>n</b> 0
t <sub>PHL</sub>	CLR	Q	C <sub>L</sub> = 50 pF		7.9	16.3	1	19.5	ns

### 6.11 Switching Characteristics: $V_{CC} = 5 V \pm 0.5 V$

over recommended operating free-air temperature range (unless otherwise noted) (see Figure 7-1)

PARAMETER	FROM	то	LOAD	T,	₄ = 25°C		-40°C to 12	25°C	UNIT
FARAMETER	(INPUT)	(OUTPUT)	CAPACITANCE	MIN	TYP	MAX	MIN	MAX	UNIT
f			C <sub>L</sub> = 15 pF	125	220		95		MHz
Imax			C <sub>L</sub> = 50 pF	85	165		65		IVII IZ
t <sub>pd</sub>	CLK	Q	C <sub>L</sub> = 15 pF		4.5	9	1	11.5	-
t <sub>PHL</sub>	CLR	Q	0 <u></u> - 15 pi		4.2	8.6	1	11	ns
t <sub>pd</sub>	CLK	Q	C <sub>L</sub> = 50 pF		6	11	1	13	
t <sub>PHL</sub>	CLR	Q	0L = 30 pr		5.8	10.6	1	13	ns

## 6.12 Noise Characteristics<sup>(1)</sup>

 $V_{CC}$  = 3.3 V,  $C_L$  = 50 pF,  $T_A$  = 25°C

	PARAMETER	SN74	_V164A-	Q1	UNIT
	FARAMETER	MIN	TYP	MAX	UNIT
V <sub>OL(P)</sub>	Quiet output, maximum dynamic V <sub>OL</sub>		0.28	0.8	V
V <sub>OL(V)</sub>	Quiet output, minimum dynamic V <sub>OL</sub>		-0.22	-0.8	V





### $V_{CC}$ = 3.3 V, $C_L$ = 50 pF, $T_A$ = 25°C

	PARAMETER	SN74	LV164A-0	ຊ1	UNIT
	FARAIMETER	MIN	TYP	MAX	UNIT
V <sub>OH(V)</sub>	Quiet output, minimum dynamic V <sub>OH</sub>		3.09		V
V <sub>IH(D)</sub>	High-level dynamic input voltage	2.31			V
V <sub>IL(D)</sub>	Low-level dynamic input voltage			0.99	V

(1) Characteristics are for surface-mount packages only.

# 6.13 Operating Characteristics

T<sub>A</sub> = 25°C

	PARAMETER	TEST C	ONDITIONS	V <sub>cc</sub>	ТҮР	UNIT
C	Power dissipation capacitance	C <sub>L</sub> = 50 pF,	f = 10 MHz	3.3 V	48.1	nΕ
Cpd	Power dissipation capacitance	C <sub>L</sub> = 50 pr,		5 V	47.5	μг

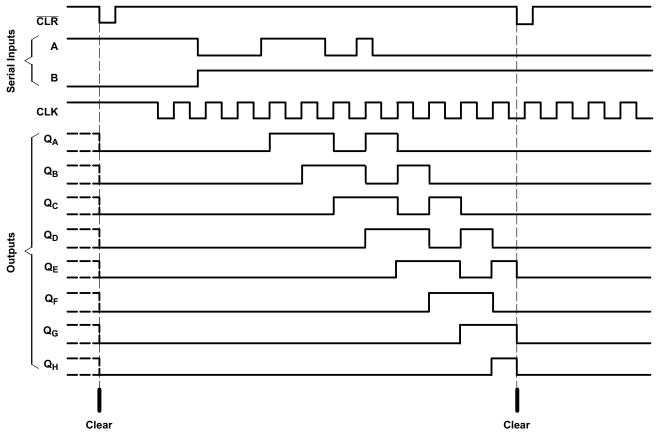
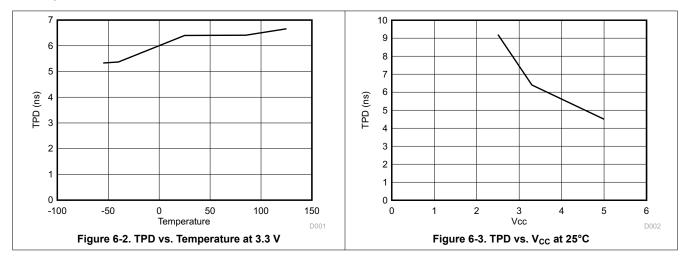


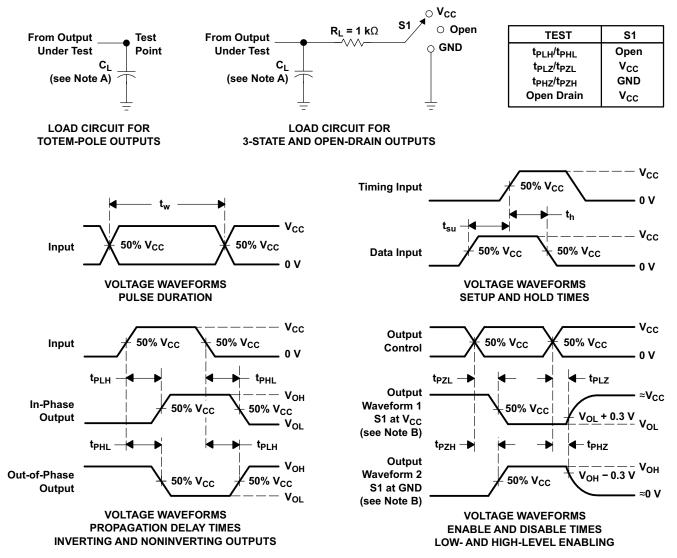
Figure 6-1. Typical Clear, Shift, and Clear Sequences



## 6.14 Typical Characteristics



## 7 Parameter Measurement Information



NOTES: A. C<sub>L</sub> includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low, except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high, except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  1 MHz, Z<sub>O</sub> = 50  $\Omega$ , t<sub>r</sub>  $\leq$  3 ns, t<sub>f</sub>  $\leq$  3 ns.
- D. The outputs are measured one at a time, with one input transition per measurement.
- E.  $t_{PL7}$  and  $t_{PH7}$  are the same as  $t_{dis}$ .
- F.  $t_{PZL}$  and  $t_{PZH}$  are the same as  $t_{en}$ .
- G.  $t_{PHL}$  and  $t_{PLH}$  are the same as  $t_{pd}$ .
- H. All parameters and waveforms are not applicable to all devices.

#### Figure 7-1. Load Circuit and Voltage Waveforms



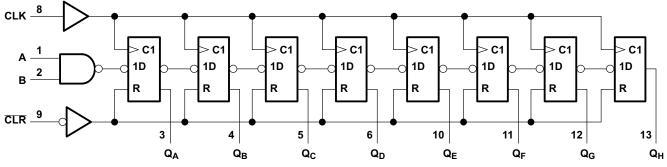
## 8 Detailed Description

### 8.1 Overview

The SN74LV164A-Q1 devices are 8-bit parallel-out serial shift registers designed for 2-V to 5.5-V V<sub>CC</sub> operation.

These devices feature NAND-gated serial (A and B) inputs and an asynchronous clear (CLR) input. The gated serial inputs permit complete control over incoming data, as a low at either input inhibits entry of the new data and resets the first flip-flop to the low level at the next clock pulse. A high-level input enables the other input, which then determines the state of the first flip-flop. Data at the serial inputs can be changed while the clock is high or low, provided the minimum setup time requirements are met. Clocking occurs on the low-to-high-level transition of the clock (CLK) input.

### 8.2 Functional Block Diagram



Pin numbers shown are for the D, DB, DGV, J, NS, PW, RGY, and W packages.

#### 8.3 Feature Description

The wide operating range allows the device to be used in a variety of systems that use different logic levels. The low propagation delay allows fast switching and higher speeds of operation. In addition, the low ground bounce stabilizes the performance of non-switching outputs while another output is switching.

#### 8.4 Device Functional Modes

NPUTS		OUTPUTS					
K A	В	Q <sub>A</sub>	Q <sub>B</sub>	Q <sub>H</sub>			
Х	Х	L	L	L			
Х	Х	Q <sub>A0</sub>	$Q_{B0}$	Q <sub>H0</sub>			
Н	Н	н	Q <sub>An</sub>	Q <sub>Gn</sub>			
L	Х	L	Q <sub>An</sub>	Q <sub>Gn</sub>			
Х	L	L	Q <sub>An</sub>	Q <sub>Gn</sub>			
	X X H L	K A B   X X X   X X X   H H H   L X	K A B Q <sub>A</sub> X X L   X X Q <sub>A0</sub> H H H   L X L	K A B Q <sub>A</sub> Q <sub>B</sub> X X L L   X X Q <sub>A0</sub> Q <sub>B0</sub> H H H Q <sub>An</sub> L X L Q <sub>An</sub>			

#### Table 8-1. Function Table<sup>(1)(2)</sup>

 Q<sub>A0</sub>, Q<sub>B0</sub>, Q<sub>H0</sub> = the level of Q<sub>A</sub>, Q<sub>B</sub>, or Q<sub>H</sub>, respectively, before the indicated steady-state input conditions were established.

(2) Q<sub>An</sub>, Q<sub>Gn</sub> = the level of Q<sub>A</sub> or Q<sub>G</sub> before the most recent ↑ transition of the clock: indicates a 1-bit shift.



## 9 Application and Implementation

#### Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

### 9.1 Application Information

The SN74LV164A-Q1 is a low drive CMOS device that can be used for a multitude of bus interface type applications where output ringing is a concern. The low-drive and slow-edge rates will minimize overshoot and undershoot on the outputs.

#### 9.2 Typical Application

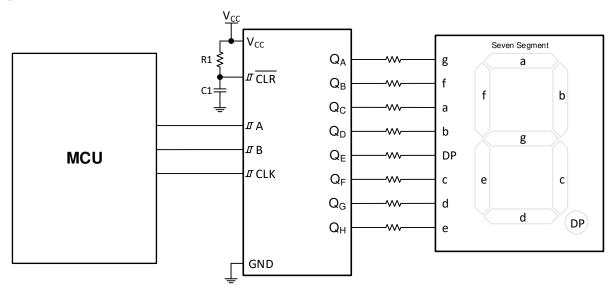


Figure 9-1. Typical Application Schematic

#### 9.2.1 Design Requirements

This device uses CMOS technology and has balanced output drive. Take care to avoid bus contention because it can drive currents that would exceed maximum limits. The high drive will also create fast edges into light loads so consider routing and load conditions to prevent ringing.

#### 9.2.2 Detailed Design Procedure

- Recommended input conditions:
  - Rise time and fall time specs. See ( $\Delta t/\Delta V$ ) in *Recommended Operating Conditions*.
  - Specified high and low level. See (V<sub>IH</sub> and V<sub>II</sub>) in *Recommended Operating Conditions*.
  - Inputs are overvoltage tolerant allowing them to go as high as 5.5 V at any valid  $V_{CC}$ .
- Recommended output conditions:
  - Load currents should not exceed 25 mA per output and 50 mA total for the part.
  - Outputs should not be pulled above V<sub>CC</sub>.

#### 9.2.3 Application Curves

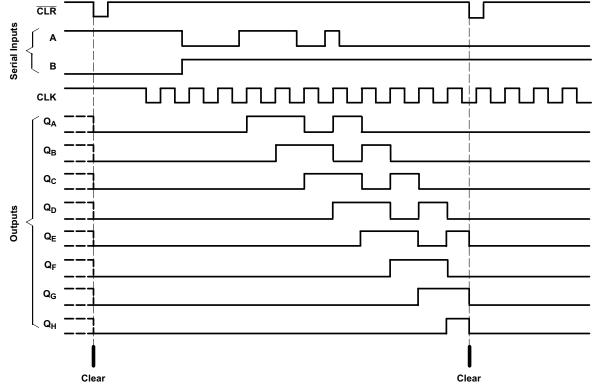


Figure 9-2. Application Timing Diagram

## **10 Power Supply Recommendations**

The power supply can be any voltage between the minimum and maximum supply voltage rating located in the *Recommended Operating Conditions*. Each V<sub>CC</sub> terminal should have a good bypass capacitor to prevent power disturbance. For devices with a single supply, TI recommends a 0.1- $\mu$ F capacitor and if there are multiple V<sub>CC</sub> terminals then TI recommends a 0.01- $\mu$ F or 0.022- $\mu$ F capacitor for each power terminal. Multiple bypass capacitors can be paralleled to reject different frequencies of noise. Frequencies of 0.1  $\mu$ F and 1  $\mu$ F are commonly used in parallel. The bypass capacitor should be installed as close as possible to the power terminal for best results.



# 11 Layout 11.1 Layout Guidelines

When using multiple bit logic devices inputs should not ever float.

In many cases, functions or parts of functions of digital logic devices are unused, for example, when only two inputs of a triple-input AND gate are used or only three of the four buffer gates are used. Such input pins should not be left unconnected because the undefined voltages at the outside connections result in undefined operational states. Specified below are the rules that must be observed under all circumstances. All unused inputs of digital logic devices must be connected to a high or low bias to prevent them from floating. The logic level that should be applied to any particular unused input depends on the function of the device. Generally they will be tied to GND or  $V_{CC}$  whichever make more sense or is more convenient. Floating outputs is generally acceptable, unless the part is a transceiver. If the transceiver has an output enable pin it will disable the outputs section of the part when asserted. This will not disable the input section of the I.O's so they also cannot float when disabled.

## 11.2 Layout Example



Figure 11-1. Layout Example



## 12 Device and Documentation Support

### 12.1 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Subscribe to updates* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

#### **12.2 Support Resources**

TI E2E<sup>™</sup> support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

Linked content is provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

#### 12.3 Trademarks

TI E2E<sup>™</sup> is a trademark of Texas Instruments.

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#### 12.4 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

#### 12.5 Glossary

TI Glossary This glossary lists and explains terms, acronyms, and definitions.

### 13 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.



## PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead finish/ Ball material	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
SN74LV164AQWBQARQ1	ACTIVE	WQFN	BQA	14	3000	RoHS & Green	(6) NIPDAU	Level-1-260C-UNLIM	-40 to 125	LVA164	Samples

<sup>(1)</sup> The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

**PREVIEW:** Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

<sup>(2)</sup> RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

**RoHS Exempt:** TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

<sup>(3)</sup> MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

<sup>(4)</sup> There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

<sup>(5)</sup> Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

<sup>(6)</sup> Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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#### OTHER QUALIFIED VERSIONS OF SN74LV164A-Q1 :



Catalog : SN74LV164A

NOTE: Qualified Version Definitions:

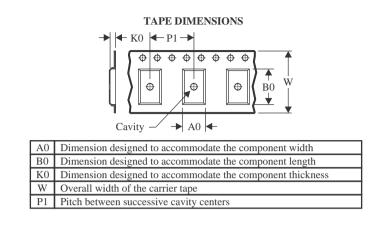
Catalog - TI's standard catalog product



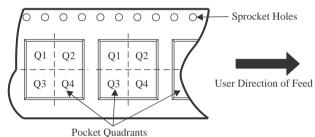
www.ti.com

## TAPE AND REEL INFORMATION





#### QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



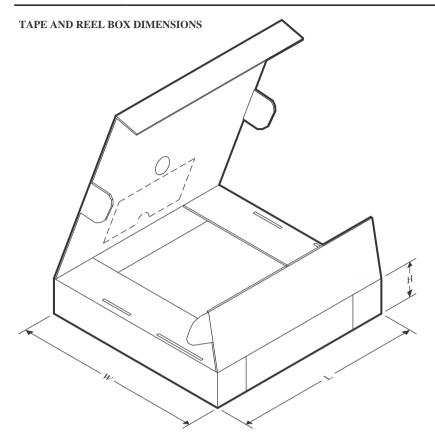
*All dimensions are nominal												
Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN74LV164AQWBQARQ1	WQFN	BQA	14	3000	180.0	12.4	2.8	3.3	1.1	4.0	12.0	Q1



www.ti.com

# PACKAGE MATERIALS INFORMATION

19-Dec-2022



\*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN74LV164AQWBQARQ1	WQFN	BQA	14	3000	210.0	185.0	35.0

# **BQA 14**

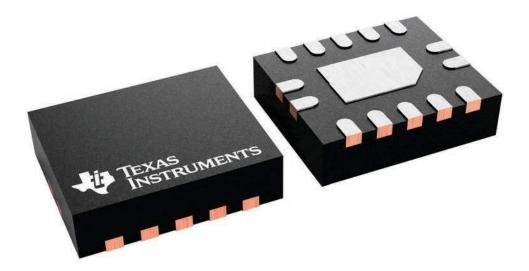
2.5 x 3, 0.5 mm pitch

# **GENERIC PACKAGE VIEW**

# WQFN - 0.8 mm max height

PLASTIC QUAD FLATPACK - NO LEAD

This image is a representation of the package family, actual package may vary. Refer to the product data sheet for package details.





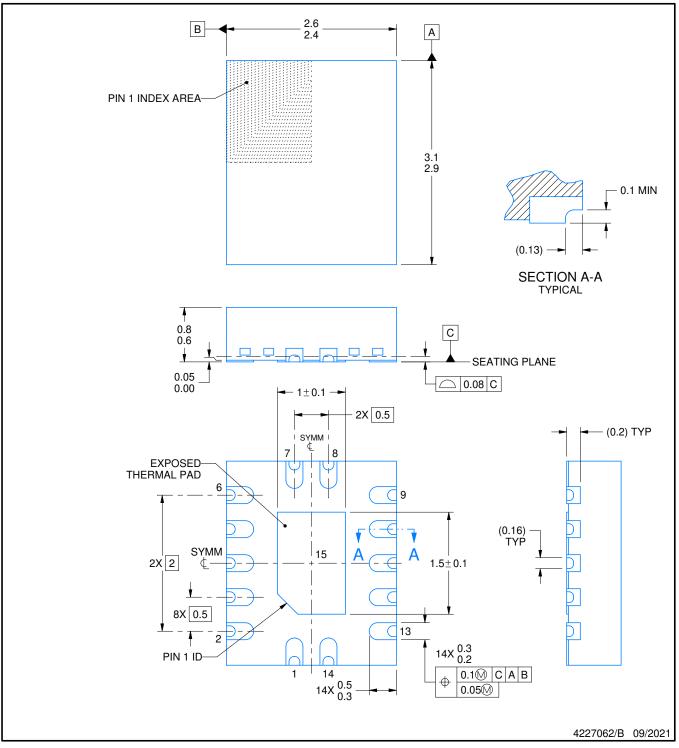
# **BQA0014B**



# **PACKAGE OUTLINE**

# WQFN - 0.8 mm max height

PLASTIC QUAD FLATPACK - NO LEAD



NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M. 2. This drawing is subject to change without notice.
- 3. The package thermal pad must be soldered to the printed circuit board for thermal and mechanical performance.

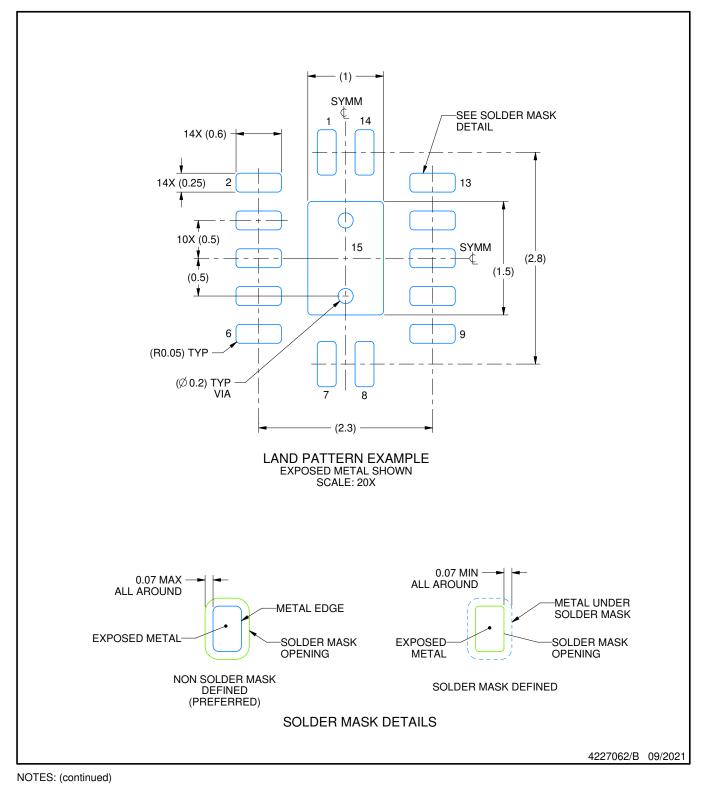


# **BQA0014B**

# **EXAMPLE BOARD LAYOUT**

## WQFN - 0.8 mm max height

PLASTIC QUAD FLATPACK - NO LEAD



 This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).

5. Vias are optional depending on application, refer to device data sheet. If any vias are implemented, refer to their locations shown on this view. It is recommended that vias under paste be filled, plugged or tented.

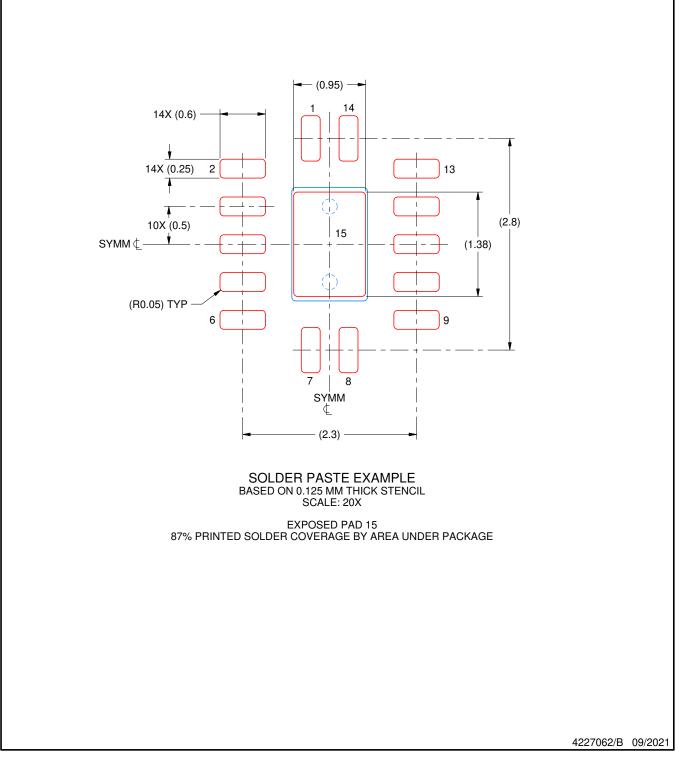


# BQA0014B

# **EXAMPLE STENCIL DESIGN**

# WQFN - 0.8 mm max height

PLASTIC QUAD FLATPACK - NO LEAD



NOTES: (continued)

6. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.



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